
Pin Descriptions

| Pin Names | Description |
| :--- | :--- |
| $\overline{O E}$ | Output Enable Input (Active LOW) |
| $T / \bar{R}$ | Transmit/Receive Input |
| $A_{0}-A_{7}$ | Side A Inputs or TRI-STATE Outputs |
| $B_{0}-B_{7}$ | Side B Inputs or TRI-STATE Outputs |

Truth Table

| Inputs |  | Output |
| :---: | :---: | :---: |
| $\overline{\mathbf{O E}}$ | $\mathbf{T} / \overline{\mathbf{R}}$ |  |
| L | L | Bus B Data to Bus A |
| L | H | Bus A Data to Bus B |
| H | X | High Z State |

H = HIGH Voltage Level
$\mathrm{L}=$ LOW Voltage Level
$X=$ Immaterial
Logic Diagram


Absolute Maximum Ratings (Note 1)
If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature
$-65^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+175^{\circ} \mathrm{C}$
$-55^{\circ} \mathrm{C}$ to $+150^{\circ} \mathrm{C}$
-0.5 V to +7.0 V
-0.5 V to +7.0 V
-30 mA to +5.0 mA
-0.5 V to 5.5 V
-0.5 V to $\mathrm{V}_{\mathrm{CC}}$
twice the rated $\mathrm{I}_{\mathrm{OL}}(\mathrm{mA})$

DC Latchup Source Current $-500 \mathrm{~mA}$ Over Voltage Latchup (I/O) 10 V
Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.
Note 2: Either voltage limit or current limit is sufficient to protect inputs.
Recommended Operating Conditions
Free Air Ambient Temperature

| Military | $-55^{\circ} \mathrm{C}$ to $+125^{\circ} \mathrm{C}$ |
| :--- | ---: |
| Commercial | $-40^{\circ} \mathrm{C}$ to $+85^{\circ} \mathrm{C}$ |
| Supply Voltage |  |
| $\quad$ Military | +4.5 V to +5.5 V |
| Commercial | +4.5 V to +5.5 V |
| Minimum Input Edge Rate | $(\Delta \mathrm{V} / \Delta \mathrm{t})$ |
| Data Input | $50 \mathrm{mV} / \mathrm{ns}$ |
| Enable Input | $20 \mathrm{mV} / \mathrm{ns}$ |

DC Electrical Characteristics

| Symbol | Parameter |  | ABT245 |  | Units | Vcc | Conditions |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  |  | Min | Typ Max |  |  |  |
| $\mathrm{V}_{\mathrm{IH}}$ | Input HIGH Voltage |  | 2.0 |  | V |  | Recognized HIGH Signal |
| $\mathrm{V}_{\text {IL }}$ | Input LOW Voltage |  |  | 0.8 | V |  | Recognized LOW Signal |
| $V_{C D}$ | Input Clamp Diode Voltage |  |  | -1.2 | V | Min | $\mathrm{I}_{\mathrm{N}}=-18 \mathrm{~mA}(\overline{\mathrm{OE}, \mathrm{T} / \overline{\mathrm{R}})}$ |
| $\mathrm{V}_{\mathrm{OH}}$ | Output HIGH Voltage | 54ABT/74ABT | 2.5 |  | V | Min | $\mathrm{IOH}=-3 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
|  |  | 54ABT | 2.0 |  | V | Min | $\mathrm{I}_{\mathrm{OH}}=-24 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
|  |  | 74ABT | 2.0 |  | V | Min | $\mathrm{I}_{\mathrm{OH}}=-32 \mathrm{~mA}\left(\mathrm{~A}_{n}, \mathrm{~B}_{\mathrm{n}}\right)$ |
| $\mathrm{V}_{\mathrm{OL}}$ | Output LOW Voltage | 54ABT |  | 0.55 | V | Min | $\mathrm{I}_{\mathrm{OL}}=48 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
|  |  | 74ABT |  | 0.55 |  |  | $\mathrm{I}_{\mathrm{OL}}=64 \mathrm{~mA}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| $\mathrm{I}_{\mathrm{IH}}$ | Input HIGH Current |  |  | $\begin{aligned} & 5 \\ & 5 \end{aligned}$ | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=2.7 \mathrm{~V}(\overline{\mathrm{OE},} \mathrm{~T} / \overline{\mathrm{R}})(\text { Note } 3) \\ & \mathrm{V}_{\mathrm{IN}}=\mathrm{V}_{\mathrm{CC}}(\overline{\mathrm{OE}, \mathrm{~T}} / \overline{\mathrm{R}}) \end{aligned}$ |
| $\mathrm{I}_{\mathrm{BVI}}$ | Input HIGH Current Breakdown Test |  |  | 7 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=7.0 \mathrm{~V}(\overline{\mathrm{OE}, \mathrm{T} / \overline{\mathrm{R}})}$ |
| $\mathrm{I}_{\text {BVIT }}$ | Input HIGH Current Breakdown Test (I/O) |  |  | 100 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\mathrm{IN}}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| IIL | Input LOW Current |  |  | $\begin{aligned} & -5 \\ & -5 \end{aligned}$ | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \mathrm{V}_{\mathrm{IN}}=0.5 \mathrm{~V}(\overline{\mathrm{OE}, \mathrm{~T}} / \overline{\mathrm{R}})(\text { Note } 3) \\ & \mathrm{V}_{\mathrm{IN}}=0.0 \mathrm{~V}(\overline{\mathrm{OE}, \mathrm{~T}} / \overline{\mathrm{R}}) \end{aligned}$ |
| $\mathrm{V}_{\text {ID }}$ | Input Leakage Test |  | 4.75 |  | V | 0.0 | $\mathrm{I}_{\mathrm{ID}}=1.9 \mu \mathrm{~A}(\overline{\mathrm{OE}}, \mathrm{~T} / \overline{\mathrm{R}})$ All Other Pins Grounded |
| $\mathrm{IIH}+\mathrm{I}_{\text {OZH }}$ | Output Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | 0-5.5V | $\mathrm{V}_{\text {OUT }}=2.7 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right) ; \overline{\mathrm{OE}}=2.0 \mathrm{~V}$ |
| $\mathrm{IIL}+\mathrm{I}_{\text {OZL }}$ | Output Leakage Current |  |  | -50 | $\mu \mathrm{A}$ | 0-5.5V | $\mathrm{V}_{\text {OUT }}=0.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right) ; \overline{\mathrm{OE}}=2.0 \mathrm{~V}$ |
| los | Output Short-Circuit Current |  | -100 | -275 | mA | Max | $\mathrm{V}_{\text {OUT }}=0.0 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |
| ICEX | Output High Leakage Current |  |  | 50 | $\mu \mathrm{A}$ | Max | $\mathrm{V}_{\text {OUT }}=\mathrm{V}_{\text {CC }}\left(A_{n}, B_{n}\right)$ |
| Izz | Bus Drainage Test |  |  | 100 | $\mu \mathrm{A}$ | 0.0 | $\mathrm{V}_{\text {OUT }}=5.5 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$; <br> All Others GND |
| ICCH | Power Supply Current |  |  | 50 | $\mu \mathrm{A}$ | Max | All Outputs HIGH |
| $\mathrm{I}_{\text {CCL }}$ | Power Supply Current |  |  | 30 | mA | Max | All Outputs LOW |
| ICCZ | Power Supply Current |  |  | 50 | $\mu \mathrm{A}$ | Max | $\begin{aligned} & \overline{\mathrm{OE}}=\mathrm{V}_{\mathrm{CC}}, \mathrm{~T} / \overline{\mathrm{R}}=\mathrm{GND} \text { or } \mathrm{V}_{\mathrm{CC}} ; \\ & \text { All Other } \mathrm{GND} \text { or } \mathrm{V}_{\mathrm{CC}} \end{aligned}$ |

Note 3: Guaranteed but not tested.


Extended AC Electrical Characteristics (solc package)

| Symbol | Parameter | 74ABT |  |  | 74ABT |  | 74ABT |  | Units |
| :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: | :---: |
|  |  | $\begin{gathered} -40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ <br> 8 Outputs Switching (Note 4) |  |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=250 \mathrm{pF} \\ 1 \text { Output Switching } \\ \text { (Note 5) } \end{gathered}$ |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=250 \mathrm{pF} \end{gathered}$ <br> 8 Outputs Switching (Note 6) |  |  |
|  |  | Min | Typ | Max | Min | Max | Min | Max |  |
| $\begin{aligned} & \mathrm{t}_{\mathrm{PZH}} \\ & \mathrm{t}_{\mathrm{PZLL}} \\ & \hline \end{aligned}$ | Output Enable Time | $\begin{aligned} & 1.5 \\ & 1.5 \end{aligned}$ |  | $\begin{aligned} & 6.5 \\ & 6.5 \end{aligned}$ | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ | $\begin{aligned} & 7.5 \\ & 7.5 \end{aligned}$ | $\begin{aligned} & 2.5 \\ & 2.5 \end{aligned}$ | $\begin{gathered} 9.5 \\ 11.0 \end{gathered}$ | ns |
| tpHZ <br> tpLZ | Output Disable Time | $\begin{aligned} & 1.0 \\ & 1.0 \end{aligned}$ |  | $\begin{aligned} & \hline 6.5 \\ & 5.6 \end{aligned}$ | (Note 7) |  | (Note 7) |  | ns |

Note 4: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.).
Note 5: This specification is guaranteed but not tested. The limits represent propagation delay with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load. This specification pertains to single output switching only.
Note 6: This specification is guaranteed but not tested. The limits represent propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.) with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.
Note 7: The TRI-STATE delays are dominated by the RC network ( $500 \Omega, 250 \mathrm{pF}$ ) on the output and have been excluded from the datasheet.
Skew (SOIC package)

| Symbol | Parameter | 74ABT | 74ABT | Units |
| :---: | :---: | :---: | :---: | :---: |
|  |  | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=50 \mathrm{pF} \end{gathered}$ <br> 8 Outputs Switching (Note 3) | $\begin{gathered} \mathrm{T}_{\mathrm{A}}=-40^{\circ} \mathrm{C} \text { to }+85^{\circ} \mathrm{C} \\ \mathrm{~V}_{\mathrm{CC}}=4.5 \mathrm{~V}-5.5 \mathrm{~V} \\ \mathrm{C}_{\mathrm{L}}=250 \mathrm{pF} \end{gathered}$ <br> 8 Outputs Switching <br> (Note 4) |  |
|  |  | Max | Max |  |
| toshl <br> (Note 1) | Pin to Pin Skew HL Transitions | 1.3 | 2.3 | ns |
| tosth <br> (Note 1) | Pin to Pin Skew <br> LH Transitions | 1.0 | 1.8 | ns |
| $t_{P S}$ <br> (Note 5) | Duty Cycle LH-HL Skew | 2.0 | 3.5 | ns |
| tost <br> (Note 1) | Pin to Pin Skew LH/HL Transitions | 2.0 | 3.5 | ns |
| tpV <br> (Note 2) | Device to Device Skew LH/HL Transitions | 2.0 | 3.5 | ns |

Note 1: Skew is defined as the absolute value of the difference between the actual propagation delays for any two separate outputs of the same device. The specification applies to any outputs switching HIGH to LOW ( $\mathrm{t}_{\mathrm{OSHL}}$ ), LOW to HIGH (tOSLH), or any combination switching LOW to HIGH and/or HIGH to LOW (tost). The specification is guaranteed but not tested.
Note 2: Propagation delay variation for a given set of conditions (i.e., temperature and $V_{C C}$ ) from device to device. This specification is guaranteed but not tested. Note 3: This specification is guaranteed but not tested. The limits apply to propagation delays for all paths described switching in phase (i.e., all low-to-high, high-to-low, etc.)
Note 4: These specifications guaranteed but not tested. The limits represent propagation delays with 250 pF load capacitors in place of the 50 pF load capacitors in the standard AC load.
Note 5: This describes the difference between the delay of the LOW-to-HIGH and the HIGH-to-LOW transition on the same pin. It is measured across all the outputs (drivers) on the same chip, the worst (largest delta) number is the guaranteed specification. This specification is guaranteed but not tested.

## Capacitance

| Symbol | Parameter | Typ | Units | Conditions <br> $\mathbf{T}_{\mathbf{A}}=\mathbf{2 5} \mathbf{C}$ |
| :---: | :---: | :---: | :---: | :---: |
| $\mathrm{C}_{I \mathrm{~N}}$ | Input Capacitance | 5.0 | pF | $\mathrm{V}_{\mathrm{CC}}=0 \mathrm{~V}(\overline{\mathrm{OE}, \mathrm{T} / \overline{\mathrm{R}})}$ |
| $\mathrm{C}_{I / \mathrm{O}}$ (Note 1) | I/O Capacitance | 11.0 | pF | $\mathrm{V}_{\mathrm{CC}}=5.0 \mathrm{~V}\left(\mathrm{~A}_{\mathrm{n}}, \mathrm{B}_{\mathrm{n}}\right)$ |

Note 1: $\mathrm{C}_{\mathrm{I} / \mathrm{O}}$ is measured at frequency $\mathrm{f}=1 \mathrm{MHz}$, per MIL-STD-883B, Method 3012.


Dashed lines represent design characteristics; for specified guarantees, refer to AC Characteristics Table


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## AC Loading



TL/F/10945-6
*Includes jig and probe capacitance
FIGURE 1. Standard AC Test Load
F/10945-6


TL/F/10945-7
FIGURE 2a. Test Input Signal Levels

| Amplitude | Rep. Rate | $\mathbf{t}_{\mathbf{w}}$ | $\mathbf{t}_{\mathbf{r}}$ | $\mathbf{t}_{\mathbf{f}}$ |
| :---: | :---: | :---: | :---: | :---: |
| 3.0 V | 1 MHz | 500 ns | 2.5 ns | 2.5 ns |

FIGURE 2b. Test Input Signal Requirements

## AC Waveforms



TL/F/10945-8
FIGURE 3. Propagation Delay Waveforms for Inverting and Non-Inverting Functions


TL/F/10945-9
FIGURE 4. Propagation Delay, Pulse Width Waveforms


FIGURE 5. TRI-STATE Output HIGH and LOW Enable and Disable Times


## Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:


L = Leadless Ceramic Chip Carrier (LCC)
$\mathrm{F}=$ Flatpak
MSA = Shrink Small Outline (EIAJ SSOP, Type II)
SJ = Small Outline (SOIC EIAJ)
MTC $=$ Molded Thin Shrink Small Outline (TSSOP)

Physical Dimensions inches (millimeters)


Physical Dimensions inches (millimeters) (Continued)



54ABT/74ABT245 Octal Bidirectional Transceiver with TRI-STATE Outputs
Physical Dimensions inches (millimeters) (Continued)


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74ABT245 - http://www.ti.com/product/74abt245?HQS=TI-null-null-dscatalog-df-pf-null-wwe
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